

Form PTO-1449 (MODIFIED)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 039153-0405 (F0945)		SERIAL NO. 09/820,143	
INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>				APPLICANT Uzodinma Okoroanyanwu et al.			
				FILING DATE 03/28/2001		GROUP ART UNIT 2878	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
UM.E.	A1	6,197,687	3/06/2001	Buynoski			
UM.E.	A2	5,994,225	11/30/99	Liu et al.			
UM.E.	A3	5,876,903	3/02/99	Ng et al.			
UM.E.	A4	5,468,595	11/21/1995	Livesay			
FOREIGN PATENT DOCUMENTS							
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES NO
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
UM.E.	A5	Chiong K.G. et al. "Resist Contrast Enhancement in High Resolution Electron Beam Lithography", Journal of Vacuum Science and Technology: Part B, American Institute of Physics, New York, US, vol. 7, no. 6.					
UM.E.	A6	Patent Abstracts of Japan, vol 1999, no. 09, 30 July 1999 (1999-07-30) & JP 11 097328 A (Toshiba Corp), 9 April 1999 (1999-04-09) abstract					
EXAMINER M. El-Shammaa				DATE CONSIDERED 7.25.02			
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EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
U.M.E.	A1	6,232,048	5/15/2001	Buynoski et al.			
U.M.E.	A2	6,197,687	3/6/01	Buynoski			
U.M.E.	A3	6,110,837	8/29/00	Linliu et al.			
U.M.E.	A4	5,876,903	3/2/99	Ng et al.			
U.M.E.	A5	5,468,595	11/21/95	Livesay			
U.M.E.	A6	3,997,367	12/14/1976	Yau			

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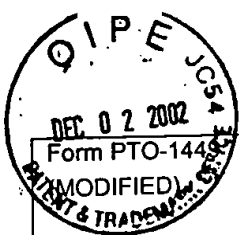
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
							YES	NO

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CM.E	A2	6,395,447	05/28/2002	Ishii et al.	430	191	
CM.E	A3	6,358,670	03/19/2002	Wong et al.	430	296	
CM.E	A4	6,319,655	11/20/2001	Wong et al.	430	311	
CM.E	A5	6,200,903	03/13/2001	Oh et al.	438	705	
CM.E	A6	6,174,818	01/16/2201	Tao et al.	438	733	
CM.E	A7	5,962,195	10/05/1999	Yen et al.	430	316	
CM.E	A8	4,446,222	05/01/1984	Kress	430	307	
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							YES	NO

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M. E. Shammaa

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		09/819,342		Shields et al			03/28/01
		09/819,343		Gabriel et al			03/28/01
		09/819,344		Okoroanyanwu et al			03/28/01
		09/819,552		Gabriel et al			03/28/01
		09/819,692		Okoroanyanwu et al			03/28/01
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		5,003,178	03/26/91	Livesay	250	492.300	

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		Livesay, W. R., "Large-area electron-beam source," Journal of Vacuum Science & Technology B, Vol. 11, No. 6, Nov./Dec. 1993, pp. 2304-2308, American Vacuum Society
		Yang, J. J. et al, "Electron Beam Processing for Spin-on Polymers and its Applications to Back-End-of-Line (BEOL) Integration," Materials Research Society Symposium Proceedings, Vol. 511, 1998, pp. 49-55, Materials Research Society
		Ross et al, "Plasma Etch Characteristics of Electron Beam Processed Photoresist," The Society of Photo-Optical Instrumentation Engineers, Vol. 2438, 1995, pp. 803-816, SPIE-The International Society for Optical Engineering
		Grün, Von A. E., "Lumineszenz-photometrische Messungen der Energieabsorption im Strahlungsfeld von Elektronenquellen Eindimensionaler Fall in Luft," Zeitschrift für Naturforschung, Vol. 12a, 1957, pp. 89-95, Publisher: Zeitschrift für Naturforschung; full English Translation attached (11 pgs.)

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